Atomic force microscopy study of tabular AgBr microcrystals (T-grains)

Author(s) SCHWARZ, UD; HAEFKE, H; JUNG, T; MEYER, E; GUNTHERODT, HJ; STEIGER, R; BOHONEK, J
Author(s) at UniBasel Meyer, Ernst ;
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The new method of atomic force microscopy has been applied to tabular AgBr microcrystals (T-grains). AgBr T-grain ensembles of different densities are imaged with high contrast and high lateral resolution. The grain surfaces appear to be very flat over large areas. On the top surfaces of single T-grains, well-developed growth hills are revealed. Heights and diameters of individual T-grains and growth hills are determined. The capabilities of atomic force microscopy are discussed in relation to the carbon replica method and scanning electron microscopy.

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